Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/512,066	MATSUURA ET AL.	
Examiner	Art Unit	
Rip A. Lee	1713	

	SEAR	RCHED	
Class	Subclass	Date	Examiner
526	336	06/4/2	061
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526	3403		
521	348		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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